**Publications**

**Books**


**Book Chapters**


**Journal Publications**


24. Kutty, K., J. S. Yuan, and S. Chen, “Evaluation of Gate Oxide Breakdown Effect on


**Conference Papers**


Conference Articles without Proceedings


Plenary and Invited Talks


### Disclosures


**Batarseh, I.** - *Interactive Electronic Book Operating Systems and Methods*, Filed on September 11, 2008, App. # 20080222552

**Batarseh, I.** - *Symbolic Switch/Linear Circuit simulator (SymCir)*, Filed on February 21, 2007.


**Liou, J. J.** and Qiang Cui - *Electrostatic Discharge (ESD) Protection Devices*, Filed on April 12, 2012, UCF-3238, U54474/163107